

Notice of References Cited

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Applicant(s)/Patent Under
Reexamination
GAIK, LEONARD J.

Examiner

THUY-VI NGUYEN

Art Unit

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0154759	10-2002	Ishii, Miruka	379/373.01
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	F	US-			
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FOREIGN PATENT DOCUMENTS

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